

# Richard Arinero

## List of Publications by Year in descending order

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37  
papers

561  
citations

623734

14  
h-index

642732

23  
g-index

37  
all docs

37  
docs citations

37  
times ranked

553  
citing authors

#	ARTICLE	IF	CITATIONS
1	High-resolution electrical characterization of RuO <sub>2</sub> -borosilicate glass composites. Journal of Alloys and Compounds, 2021, 876, 160123.	5.5	1
2	Capacitive silicon micro-electromechanical resonator for enhanced photoacoustic spectroscopy. Applied Physics Letters, 2019, 115, .	3.3	12
3	Pedestal formation of all-semiconductor gratings through GaSb oxidation for mid-IR plasmonics. Journal Physics D: Applied Physics, 2018, 51, 015104.	2.8	5
4	Stable and Unstable Spatial Modes in a Resonator with a Half-Disk Shape. Semiconductors, 2018, 52, 2046-2048.	0.5	0
5	New Insights into Dielectric Nanocomposites by EFM Imaging and Spectroscopy. , 2018, , .		0
6	Electrostatic force microscopy for the accurate characterization of interphases in nanocomposites. Beilstein Journal of Nanotechnology, 2018, 9, 2999-3012.	2.8	11
7	Half-disk laser: insight into the internal mode structure of laser resonators. Optics Express, 2018, 26, 14433.	3.4	5
8	Mid-IR plasmonic compound with gallium oxide toplayer formed by GaSb oxidation in water. Semiconductor Science and Technology, 2018, 33, 095009.	2.0	3
9	Characterization of Dielectric Nanocomposites with Electrostatic Force Microscopy. Scanning, 2017, 2017, 1-14.	1.5	21
10	Nanoscale surface charge detection in epoxy resin materials using electrostatic force spectroscopy. AIP Advances, 2016, 6, .	1.3	24
11	Magnetic flux distortion in two-phase liquid metal flow: Model experiment. Journal of Applied Physics, 2016, 119, .	2.5	5
12	Investigation of EFM capabilities for probing interphases in nanodielectric materials: A numerical study. , 2016, , .		9
13	Towards a better understanding of wood cell wall characterisation with contact resonance atomic force microscopy. Composites Part A: Applied Science and Manufacturing, 2015, 74, 69-76.	7.6	32
14	Apertureless scanning microscope probe as a detector of semiconductor laser emission. Applied Physics Letters, 2015, 106, 171105.	3.3	7
15	Impact of Single Event Gate Rupture and Latent Defects on Power MOSFETs Switching Operation. IEEE Transactions on Nuclear Science, 2014, 61, 1856-1864.	2.0	5
16	Conductive atomic force microscopy as a tool to reveal high ionising dose effects on ultra thin SiO <sub>2</sub> /Si structures. Applied Nanoscience (Switzerland), 2013, 3, 235-240.	3.1	0
17	Near field imaging of a semiconductor laser by scanning probe microscopy without a photodetector. Applied Physics Letters, 2013, 103, 053120.	3.3	14
18	Post-Irradiation-Gate-Stress on Power MOSFETs: Quantification of Latent Defects-Induced Reliability Degradation. IEEE Transactions on Nuclear Science, 2013, 60, 4166-4174.	2.0	6

#	ARTICLE	IF	CITATIONS
19	Temperature and damping effects on the frequency dependence of electrostatic force microscopy force gradients. <i>Journal of Applied Physics</i> , 2013, 114, 214315.	2.5	1
20	Numerical simulations of electrostatic interactions between an atomic force microscopy tip and a dielectric sample in presence of buried nano-particles. <i>Journal of Applied Physics</i> , 2012, 112, .	2.5	15
21	Contrast inversion in electrostatic force microscopy imaging of trapped charges: tip-sample distance and dielectric constant dependence. <i>Nanotechnology</i> , 2011, 22, 345702.	2.6	10
22	Broadband nanodielectric spectroscopy by means of amplitude modulation electrostatic force microscopy (AM-EFM). <i>Ultramicroscopy</i> , 2011, 111, 1366-1369.	1.9	25
23	High fluence 1.8MeV proton irradiation effects on n-type MOS capacitors. <i>Microelectronics Reliability</i> , 2011, 51, 2093-2096.	1.7	11
24	Influence of the surrounding ambient on the reliability of the electrical characterization of thin oxide layers using an atomic force microscope. <i>Microelectronics Reliability</i> , 2011, 51, 2097-2101.	1.7	4
25	Compatibility studies of polystyrene and poly(vinyl acetate) blends using electrostatic force microscopy. <i>Journal of Polymer Science, Part B: Polymer Physics</i> , 2011, 49, 1332-1338.	2.1	5
26	Nanoscale dielectric properties of insulating thin films: From single point measurements to quantitative images. <i>Ultramicroscopy</i> , 2010, 110, 634-638.	1.9	20
27	Imaging dielectric relaxation in nanostructured polymers by frequency modulation electrostatic force microscopy. <i>Applied Physics Letters</i> , 2010, 96, 213110.	3.3	47
28	Nanodielectric mapping of a model polystyrene-poly(vinyl acetate) blend by electrostatic force microscopy. <i>Physical Review E</i> , 2010, 81, 010801.	2.1	53
29	Determination of the nanoscale dielectric constant by means of a double pass method using electrostatic force microscopy. <i>Journal of Applied Physics</i> , 2009, 106, .	2.5	73
30	High-Energy Heavy Ion Irradiation-Induced Structural Modifications: A Potential Physical Understanding of Latent Defects. <i>IEEE Transactions on Nuclear Science</i> , 2008, 55, 2970-2974.	2.0	9
31	STRUCTURAL PROPERTIES OF PbTiO <sub>3</sub> FILMS GROWN BY MIXED REACTIVE THERMAL CO-EVAPORATION. <i>Integrated Ferroelectrics</i> , 2008, 98, 161-170.	0.7	1
32	New method for electrostatic force gradient microscopy observations and Kelvin measurements under vacuum. <i>Ultramicroscopy</i> , 2007, 107, 1027-1032.	1.9	12
33	PbTiO <sub>3</sub> thin films grown by mixed reactive thermal co-evaporation. <i>Journal of Crystal Growth</i> , 2007, 304, 383-387.	1.5	4
34	Development of ruthenium dioxide electrodes for pyroelectric devices based on lithium tantalate thin films. <i>Thin Solid Films</i> , 2007, 515, 3971-3977.	1.8	18
35	Force gradient detection under vacuum on the basis of a double pass method. <i>Review of Scientific Instruments</i> , 2006, 77, 096101.	1.3	24
36	Vibration of the cantilever in Force Modulation Microscopy analysis by a finite element model. <i>Review of Scientific Instruments</i> , 2003, 74, 104-111.	1.3	41

#	ARTICLE	IF	CITATIONS
37	Imaging the Mechanical Properties of Wood Cell Wall Layers by Atomic Force Modulation Microscopy. IAWA Journal, 2003, 24, 223-230.	2.7	28